

Docket No.: 4468-017A

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of :
KIMURA, EIJI : Confirmation No.
U.S. Patent Application No. Not yet Assigned : Group Art Unit:
Filed: *Herewith* : Examiner:

For: OPTICAL CHARACTERISTICS MEASURING APPARATUS, METHOD AND RECORDING MEDIUM

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

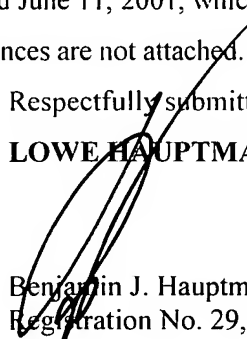
In accordance with the provisions of 37 C.F.R. 1.56, 1.97 and 1.98, the attention of the Patent and Trademark Office is hereby directed to the documents listed on the attached form PTO-1449. It is respectfully requested that the documents be expressly considered during the prosecution of this application, and that the documents be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

This Information Disclosure Statement is being filed within three months after the U.S. filing date or before the mailing date of a first Office Action on the merits. No certification or fee is required.

The references were cited by or submitted to the U.S. Patent and Trademark Office in Parent Application No. 09/877,202, filed June 11, 2001, which is relied upon for an earlier filing date under 35 USC 120. Thus copies of these references are not attached. 37 CFR 1.98 (d).

Respectfully submitted,

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INFORMATION DISCLOSURE CITATION IN AN APPLICATION (PTO-1449)				ATTY. DOCKET NO. 4468-017A		U.S. PATENT APPLICATION NO.	
				APPLICANT KIMURA, EIJI			
				FILING DATE Herewith		GROUP	
U.S. PATENT DOCUMENTS							
EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE	
	6,212,003	4/2001	Komazawa et al.				
	6,144,485	11/2000	Sugaya et al.				
	5,278,687	1/1994	Jannson et al.				
	4,997,277	3/1991	Horiguchi et al.				
	5,969,806	10/1999	Bergano				
	4,551,019	11/1985	Vella et al.				
FOREIGN PATENT DOCUMENTS							
EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
	GB 2353591 A	2/2001	GB				
	0 348235	12/1989	EP				
	WO99/43054	8/1999	WIPO				
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)							
EXAMINER				DATE CONSIDERED			

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.